Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10653838	CHANG ET AL.
Examiner	Art Unit
Chawan, Sheela C	2624

SEARCHED					
Class	Subclass	Date	Examiner		
382	141,199	4/12/07	SCC		
702	167	11	II		
ABOVE SEARCH UP- DATE.			"		

SEARCH NOTES				
Search Notes	Date	Examiner		
SEARCH EAST AND OTHER DATABASE SEE ATTACHED SEARCH HISTORY.	4/12/07	SCC		
382/141,147,151,152, 203,266,190,199.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	17	"		
396/569,570.CCLS.	11	11		
356/28,630,623,611,636,394.CCLS.	11	"		
396/569,570.CCLS.	11	!!		
348/139,135.CCLS.	11	. 11		
702/167.CCLS.	11	11		
INTERFERENCE SEARCH SEE SEARCH HISTORY PRINT OUT.	11	11		
INVENTOR NAME SEARCH.		11		
SEARCH IEEE OR INSPEC DATABASE.		"		
364/731 ABOLISH.	11	"		
395/133 ABOLISH.	n	11		
ABOVE SEARCH UPDATE .	11	19		

Class	Subclas	ss Date	Examiner
382	141,199	4/12/07	SCC
702	167	"	11